TOSHIBA 2SK1826

TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE

2 S K 1 8 2 6

HIGH SPEED SWITCHING APPLICATIONS

ANALOG SWITCH APPLICATIONS

4V Gate Drive

Low Threshold Voltage: $V_{th} = 0.8 \sim 2.5 V$

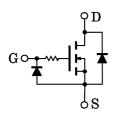
High Speed

Enhanncement-Mode

Small Package

EOUIVALENT CIRCUIT

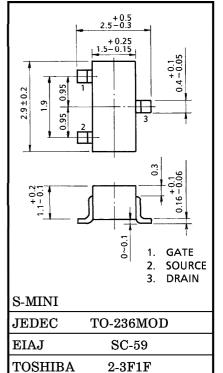
MARKING





This transistor is electrostatic sensitive device. Please handle with caution.

Unit in mm



Weight: 0.012g (Typ.)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Drain-Source Voltage	$v_{ m DS}$	DS 50		
Gate-Source Voltage	v_{GSS}	10	V	
DC Drain Current	$I_{\mathbf{D}}$	50	mA	
Drain Power Dissipation	$P_{\mathbf{D}}$	200	mW	
Channel Temperature	$\mathrm{T_{ch}}$	150	°C	
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~150	$^{\circ}\mathrm{C}$	

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARAC	TERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		$I_{ m GSS}$	$V_{GS}=10V, V_{DS}=0$	_	_	1	μ A
Drain-Source Breakdown Voltage		V _{(BR) DSS}	$I_{D} = 100 \mu A, V_{GS} = 0$	50	_	_	V
Drain Cut-off	Current	$I_{ m DSS}$	$V_{DS}=50V, V_{GS}=0$	_	_	1	μ A
Gate Threshol	d Voltage	$ m v_{th}$	V_{DS} =5V, I_{D} =0.1mA	0.8	_	2.5	V
Forward Trans Admittance	sfer	Y _{fs}	V_{DS} =5V, I_{D} =10mA	20	_	_	mS
Drain-Source ON Resistance		R _{DS} (ON)	$I_D=10$ mA, $V_{GS}=4.0$ V	_	20	50	Ω
Input Capacitance		$\mathrm{c}_{\mathrm{iss}}$	$V_{DS}=5V$, $V_{GS}=0$, $f=1MHz$	_	6.3	_	pF
Reverse Trans Capacitance	fer	$\mathrm{C}_{ extbf{rss}}$	V_{DS} =5V, V_{GS} =0, f=1MHz	_	1.3	_	pF
Output Capacitance		C_{oss}	$V_{DS}=5V$, $V_{GS}=0$, $f=1MHz$	_	5.7	_	pF
Switching Time	Turn-on Time	ton	$V_{\rm DD} = 5 \text{V}, \ I_{\rm D} = 10 \text{mA}, \ V_{\rm GS} = 0 \sim 4.0 \text{V}$	_	0.11	_	μs
	Turn-off Time	t _{off}	V _{DD} =5V, I _D =10mA, V _{GS} =0~4.0V	_	0.15	_	μs

SWITCHING TIME TEST CIRCUIT

